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## Lecture 6

### Flip-Flop and Clock Design

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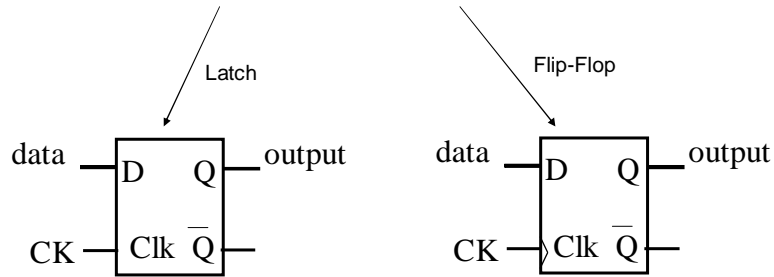
## Design Considerations

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- Basic role of clock is to perform synchronization operation in sequential logic circuits
- Clocks are used primary to drive the flip-flops in a logic chip
- Usually thousands of flops exist on the chip
- Design of the clock and the flops are related to each other so they should be studied together
- Design Issues:
  - flip-flop setup and hold times
  - clock power
  - clock latency, skew, jitter
  - impact of IR drop on clock
  - clock layout and routing
  - clock synchronization: PLL and DLL

## Clocked D Flip-flop

- Very useful FF
- Widely used in IC design for temporary storage of data
- May be *level-sensitive or edge-triggered*



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## Latch vs. Flip-flop

Latch (level-sensitive, transparent)

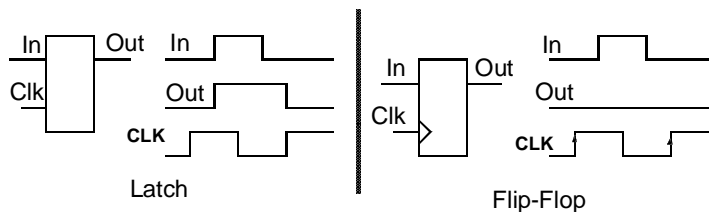
When the clock is high it passes **In** value to **Out**

When the clock is low, it holds value that **In** had when the clock fell

Flip-Flop (edge-triggered, non transparent)

On the *rising* edge of clock (pos-edge trig), it transfers the value of **In** to **Out**

It holds the value at all other times.



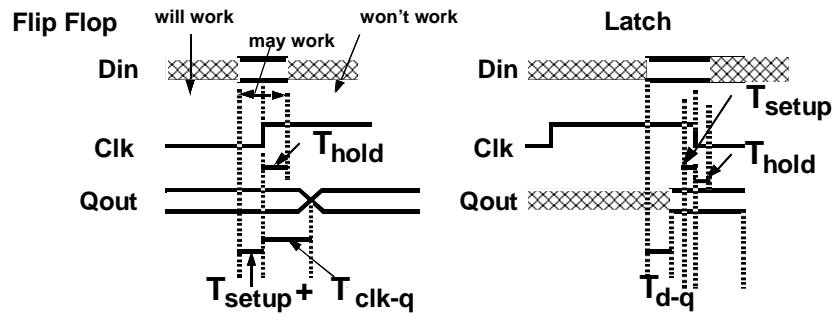
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## Clocking Overhead

FF and Latches have setup and hold times that must be satisfied:



If Din arrives before setup time and is stable after the hold time, FF will work; if Din arrives after hold time, it will fail; in between, it may or may not work; FF delays the slowest signal by the setup + clk-q delay in the worst case

Latch has small setup and hold times; but it delays the late arriving signals by  $T_{d-q}$

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## Clock Skew

- Not all clocks arrive at the same time, i.e., they may be skewed.
    - SKEW = mismatch in the delays between arrival times of clock edges at FF's
- SKEW causes two problems:

- The cycle time gets longer by the skew

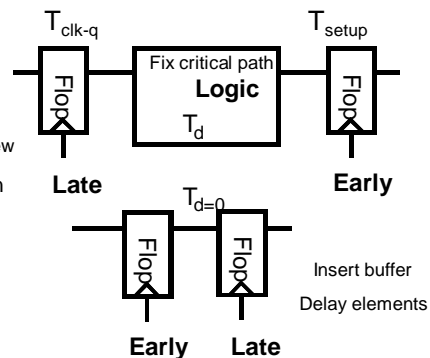
$$T_{\text{cycle}} = T_d + T_{\text{setup}} + T_{\text{clk-q}} + T_{\text{skew}}$$

Shows up as a SETUP time violation

- The part can get the wrong answer

$$\text{when } T_{\text{skew}} + T_{\text{hold}} > T_{\text{clk-q}}$$

Shows up as a HOLD time violation



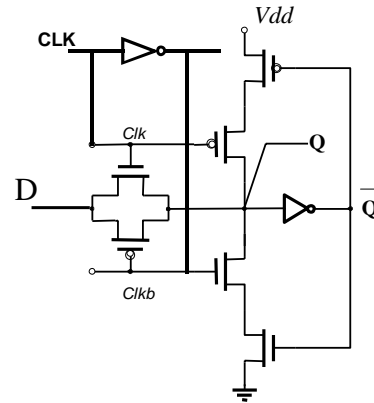
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## Transfer Gate D-Latch

- D-latch operation
  - When D arrives, if CLK is low then TG is off, and the previous output is held
  - When CLK goes high, D enters FF through TG and establishes Q and  $\bar{Q}$ 
    - If data is 1, pull up network is enabled
    - If data is 0, pull down network is enabled
    - When clock goes low, the data is latched by one of the two networks
  - Setup time: time needed to charge Q
  - Hold time: time needed to shut off CLK and turn off TG



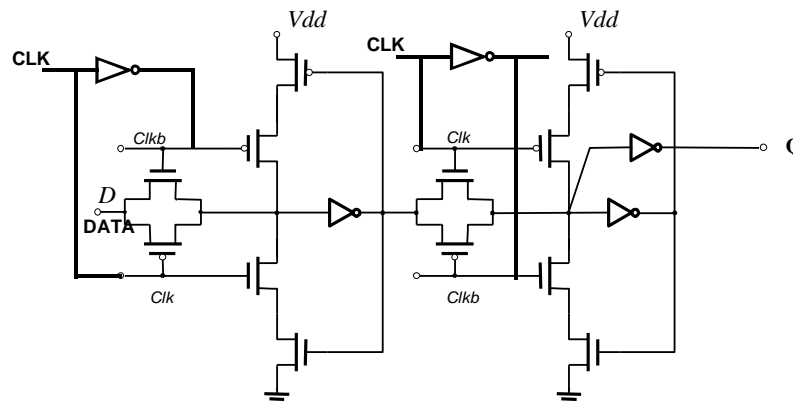
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## T-G Master-Slave D-FF

- Edge-Triggered Flip-flop

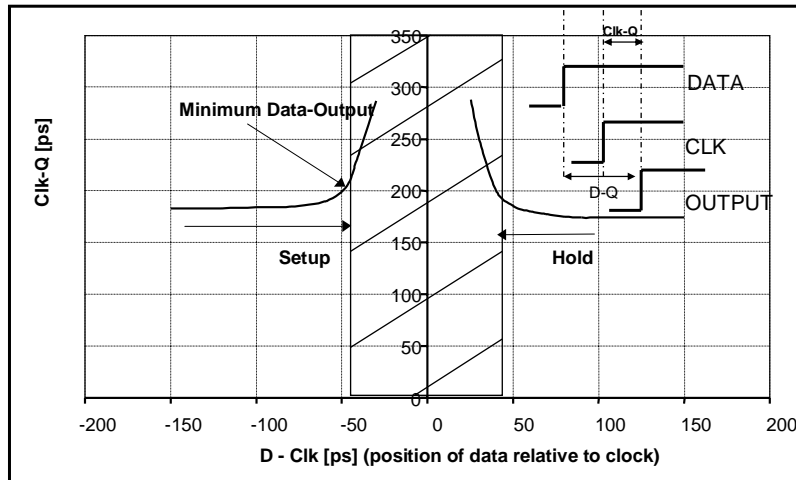


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## Delay vs. Setup/Hold Times



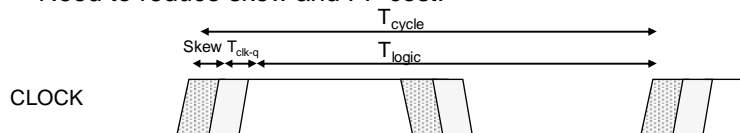
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## Overhead for a Clock

- CMOS FO4 delay is roughly  $425\text{ps}/\mu\text{m} \times L_{\text{eff}}$
- For  $0.13\mu\text{m}$ , FO4 delay  $\approx 50\text{ps}$ 
  - For a 1GHz clock, this allows  $< 20$  FO4 gate delays/cycle
- Clock overhead (including margins for setup/hold)
  - 2 FF/Latches cost about  $2 \times 1.2\text{FO4 delays} = 2\text{-}3$  FO4 delays
  - skew costs approximately 2-3 FO4 delays
- Overhead of clock is roughly 4-6 FO4 delays
- 14-16 FO4 delays left to work with for logic
- Need to reduce skew and FF cost.



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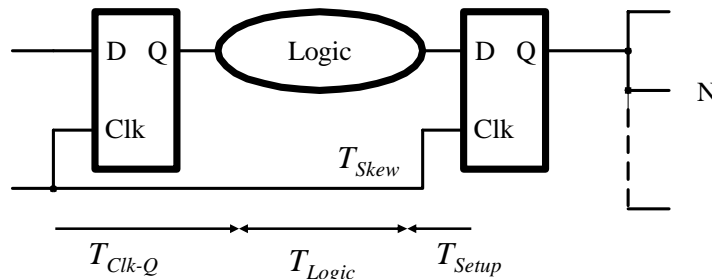
## Requirements in Flip-Flop Design

- Minimize FF overhead: small clk-q delay,  $t_{\text{setup}}$ ,  $t_{\text{hold}}$  times
- Minimize power
  - expensive packages and cooling systems
  - flops up to 20% of total power of high-performance systems
- High driving capability
  - Typical flip-flop load in a 0.18 $\mu\text{m}$  CMOS ranges from 50fF to over 200fF, with typical values of 100-150fF in critical paths
- Multiplexed or scan enabled
- Crosstalk insensitivity
  - dynamic/high impedance nodes are problematic
- Small load on clock to improve performance of clock and reduce power of clock
  - clocks can consume 40% of total chip power

## Clock Design Issues

- Clock cycle depends on a number of factors:

$$T_{\text{cycle}} = T_{\text{Clk-Q}} + T_{\text{Logic}} + T_{\text{setup}} + T_{\text{skew}}$$



## Sources of Clock Skew

Main sources:

1. Imbalance between different paths from clock source to FF's
  - interconnect length determines RC delays
  - capacitive coupling effects cause delay variations
  - buffer sizing
  - number of loads driven
2. Process variations across die
  - interconnect and devices have different statistical variations

Secondary Sources:

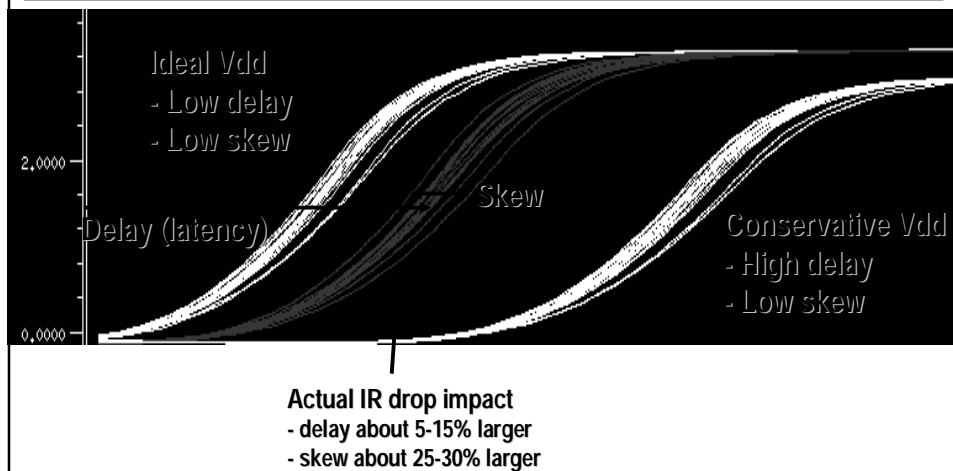
1. IR drop in power supply
2. Ldi/dt drop in supply

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## IR Drop Impacts on Clock Skew

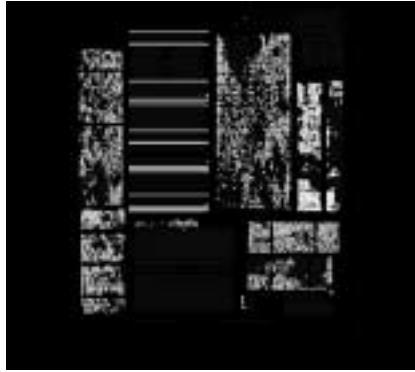


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## Effects of IR-Drop on Clock Skew



Without IR-drop



With IR-drop

Plots courtesy of Simplex Solutions, Inc.

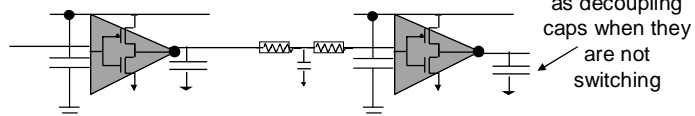
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## Reducing the Effects of IR drop and $Ldi/dt$

- Stagger the firing of buffers (bad idea: increases skew)
- Use different power grid tap points for clock buffers (but it makes routing more complicated for automated tools)
- Use smaller buffers (but it degrades edge rates/increases delay)
- Make power busses wider (requires area but should do it)
- Use more Vdd/Vss pins; adjust locations of Vdd/Vss pins
- Put in power straps where needed to deliver current
- Place decoupling capacitors wherever there is free space
- Integrate decoupling capacitors into buffer cells



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## Power dissipation in Clocks

- Significant power dissipation can occur in clocks in high-performance designs:
  - clock switches on every cycle so  $P = CV^2f$  (i.e.,  $\alpha=1$ )
  - clock capacitance can be ~nF range, say  $1\text{nF} = 1000\text{pF}$
  - assuming a power supply of 1.8V,  $CV = 1800\text{pC}$  of charge
  - if clock switches every 2ns (500MHz), that's 0.9A
  - for  $V_{DD} = 1.8\text{V}$ ,  $P = IV = 0.9(1.8) = 1.6\text{W}$  in the clock circuit alone
- Much of the power (and the skew) occurs in the final drivers due to the sizing up of buffers to drive the flip-flops
- Key to reducing the power is to examine equation  $CV^2f$  and reduce the terms wherever possible
  - $V_{DD}$  is usually given to us; would not want to reduce swing due to coupling noise, etc.
  - Look more closely at C and f

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## Reducing Power in Clocking

- Gated Clocks:
  - can gate clock signals through AND gate before applying to flip-flop; this is more of a total chip power savings
  - all clock trees should have the same type of gating whether they are used or not, and at the same level - total balance
- Reduce overall capacitance (again, shielding vs. spacing)



(a) higher total cap./less area

(b) lower cap./ more area

- Tradeoff between the two approaches due to coupling noise
- approach (a) is better for inductive noise; (b) is better for capacitive noise

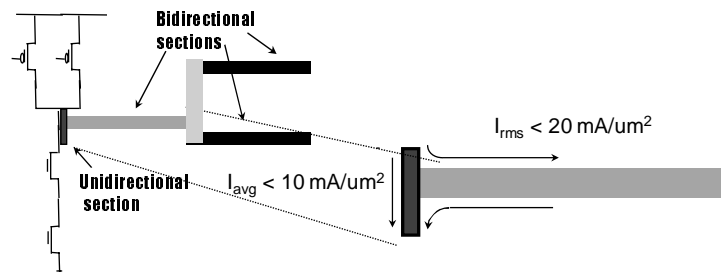
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## Signal Electromigration

- Electromigration can occur on certain signal lines
- Clocks are prone to EM failures due to large current demand on every cycle
- Since current is bidirectional, we look at RMS current which lead to Joule heating effects (thermal)
- Based on signal activity (frequency of switching)

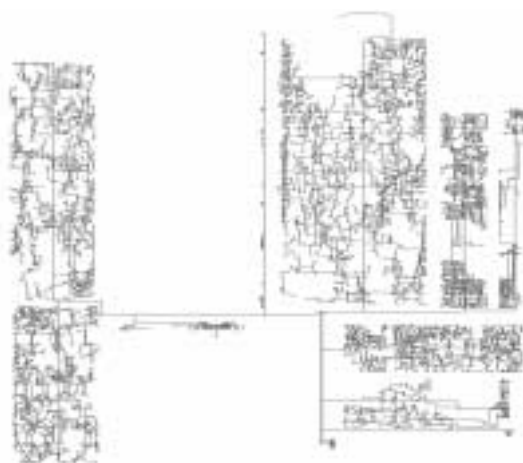


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## Clock Circuit of Multimedia Chip



Plots courtesy of Simplex Solutions, Inc.

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## Signal EM Example



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## Clock Design Objectives

- Now that we understand the role of the clock and some of the key issues, how do we design it?
  - Minimize the clock skew (in presence of IR drop)
  - Minimize the clock delay (latency)
  - Minimize the clock power (and area)
  - Maximize noise immunity (due to coupling effects)
  - Maximize the clock reliability (signal EM)
- Problems that we will have to deal with
  - Routing the clock to all flip-flops on the chip
  - Driving unbalanced loading, which will not be known until the chip is nearly completed
  - On-chip process/temperature variations

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## Clock Design and Verification

- Many design styles
  - Low-speed designs: regular signals, symmetric tree
  - Medium-speed designs: balanced H-tree
  - High-speed designs
    - Balanced buffered H-tree
    - Grid
- Clock verification is more complex in DSM
  - RC Interconnect delays
  - Signal integrity (capacitive coupling, inductance)
  - IR drop
  - Signal Electromigration
  - Clock Jitter

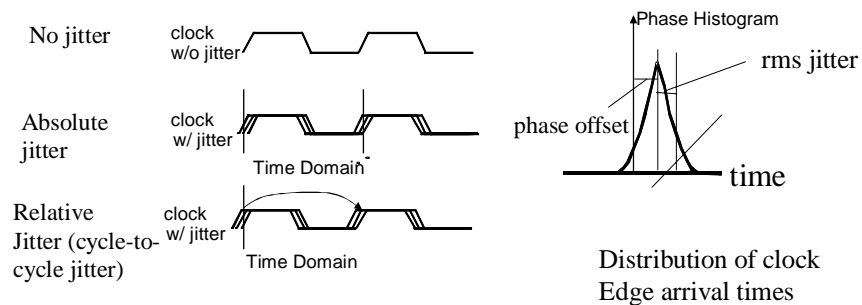
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## Clock Jitter

- Jitter is a term that applies to the shifting of a clock edge relative to its expected position due to noise (e.g., from power supply, random noise, temperature variation)
- Can be viewed as an uncertainty in the clock edge



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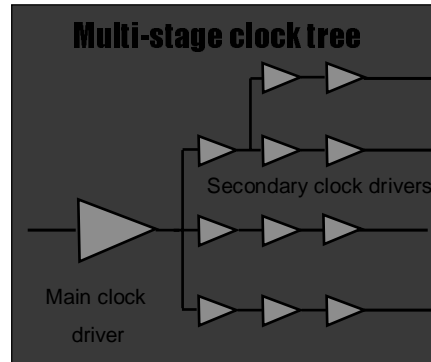
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## Clock Design

### Tree

- Minimal area cost
- Requires clock-tree management
- Use a large superbuffer to drive downstream buffers
- Balancing may be an issue



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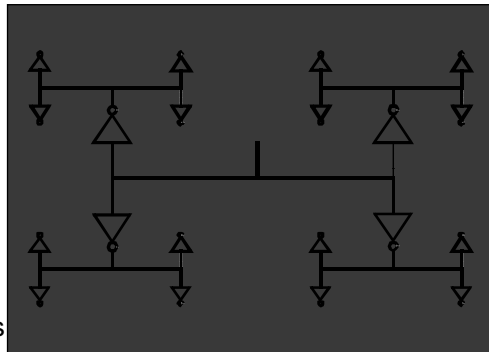
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## Clock Configurations

### H-Tree

- Place clock root at center of chip and distribute as an H structure to all areas of the chip
- Clock is delayed by an equal amount to every section of the chip
- Local skew inside blocks is kept within tolerable limits



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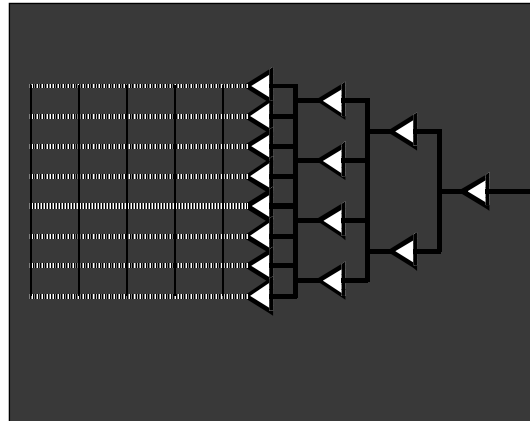
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## Clock Configurations

### Grid

- Greater area cost
- Easier skew control
- Increased power consumption
- Electromigration risk increased at drivers
- Severely restricts floorplan and routing



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## Clock Design Today

### Old methodology

- Route clock
- Route rest of nets
- Extract clock parasitics
- Perform timing verification
- Balance clock by "snaking" route in reserved areas

### Advanced Clock Verification

- IR Drop and Ldi/dt effects
- Coupling capacitance
- Electromigration checks
- Full-chip skew/slew analysis
- Jitter analysis
- Inductance Effects
- Process variations

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## Good Practices in Clock Design

- Try to achieve the lowest Latency (Super Buffer/H-tree)
- Control transition times (keep edge rates sharp)
- Use 1 type of clock buffer for good matching (except perhaps in the last leg where you need to have adjustable buffers)
- Have min/max line lengths for good matching
- Determine whether spacing or shielding provides better tradeoff
- Use integral decoupling in buffers to reduce IR and  $Ldi/dt$

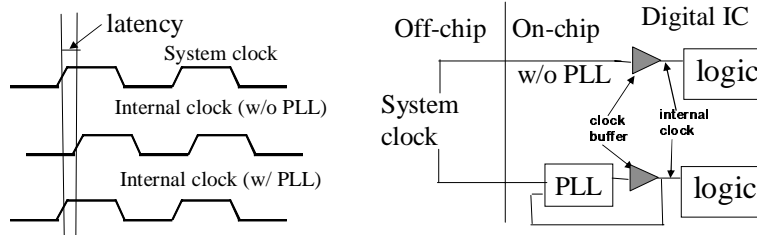
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## PLLs/DLLs

- So far in this course we have talked about clock design but not about the circuits that generate the clock and synchronize data around the clock
- These circuits are generally referred to as phase-locked loops (PLL) and delay-locked loops (DLLs)
- Applications of these circuits include: system synchronization, skew reduction, clock synthesis, clock and data synchronization

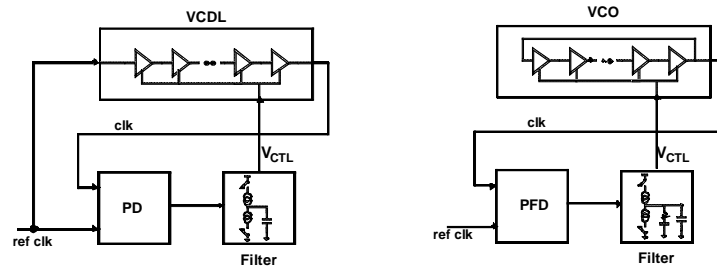


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## PLL/DLL Architecture



First order loop:

- easily stabilized
- frequency synthesis a problem
- ref clk jitter passes through

Second/Third order loop:

- stability is an issue
- frequency synthesis easy
- filtering of ref clk jitter

## PLL Vs DLL

- PLL:
  - Second/Third order loop (stability is an issue)
  - Frequency synthesis possible (uses a VCO)
  - Input jitter is filtered
  - Phase error accumulates (takes longer to acquire lock)
  - Limited frequency capture range, unlimited phase capture range.
- DLL:
  - First order loop (always stable)
  - No self-generated jitter
  - Phase error does not accumulate
  - Not able to adjust its frequency (uses VCDL)
  - Limited phase capture range
  - Very attractive alternative when no frequency synthesis required.